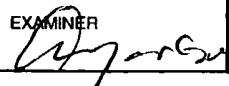
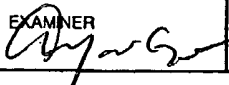


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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2471		SERIAL NO. 10/741,300			
<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> MAY 12 2004 U.S. PATENT & TRADEMARK OFFICE </div>				LIST OF ART. CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT: Trung-Tri Doan et al.	
				FILING DATE December 17, 2003		GROUP 3711			
U.S. PATENT DOCUMENTS									
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
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							Yes No		
TA	AJ	JP 01187380 A	07/89	Japan					
	AK								
	AL								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
	AM								
	AN								
	AO								
EXAMINER <i>Myer</i>		DATE CONSIDERED <i>6/28/04</i>							
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>									

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2471		SERIAL NO. PRIORITY 10/097,025		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Micron Technology, Inc.				
				FILING DATE PRIORITY March 11, 2002		GROUP PRIORITY 1763		
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	AC	5,242,539	09/1993	Kumihashi et al.	216	67		
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						Yes	No	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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	AO							
EXAMINER 		DATE CONSIDERED 6/28/04						
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
A	AJ	JP 2001220677 A	08/2001	Japan	—	—		
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	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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